

ICXOM23

23rd International Congress on X-ray Optics and Microanalysis

ICXOM23 will bring together scientists in the fields of x-ray microanalysis and those involved in optical instrumentation developments which will extend the reach of microanalysis. Although synchrotron radiation will be at the heart of the conference, since electron microscopy offers a different view of materials, the conference also welcomes contributions of recent developments in that field.

Topics

Optics for microanalysis

Scanning microscopy

Full-field imaging

Coherent Imaging

PEEM

Electron microscopy

Microdiffraction

Data analysis

Detectors



September 14-18, 2015

**Brookhaven National
Laboratory**

Long Island, New York



The conference will be held at Brookhaven National Laboratory on Long Island in New York State. The laboratory is host to the National Synchrotron Light Source and its successor, NSLS-II, pictured above (<http://www.bnl.gov/ps/>). BNL is also home to a new nanoscience center (<http://www.bnl.gov/cfn/>) and a state-of-the-art aberration-compensated TEM facility (<http://www.bnl.gov/cfn/facilities/microscopy.php>, <http://www.bnl.gov/tem/>).

Conference Chairs

Peter Siddons (BNL)

Juergen Thieme (BNL)

Organizers

Yong Chu (BNL)

Gretchen Cisco (BNL)

Andrei Fluerasu (BNL)

Mourad Idir (BNL)

Qun Shen (BNL)

Lutz Wiegart (BNL)

Nancye Wright (BNL)

Hanfei Yan (BNL)

Yimei Zhu (BNL)

Paul Zschack (BNL)

**Registration to open on
January 1, 2015**

Early registration deadline:
July 1, 2015

General registration deadline:
September 1, 2015

Abstract deadline:
April 30, 2015

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<http://www.bnl.gov/icxom23>